

TEST REPORT

Applicant/Manufacturer: AGM MOBILE LIMITED
Address: FLAT/RM 2253 22/F HOI TAI FACTORY ESTATE TSING YEUNG
CIRCUIT TUEN MUN NT HONG KONG CHINA
Report Number: 2501X79555E-RF-07B

Test Standard (s)

Item 19 of Article 2 Paragraph 1

Sample Description

Product Type: TWS Bluetooth Headset
Model No.: AGM OPEN BUDS 1
Multiple Model(s) No.: N/A
Trade Mark: N/A
Date Received: 2025-09-26
Issue Date: 2025-12-23

Test Result:	Pass▲
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▲ In the configuration tested, the EUT complied with the standards above.

Prepared and Checked By:

Ruby Huang

Ruby Huang
RF Engineer

Approved By:

Nancy Wang

Nancy Wang
RF Supervisor

Note: The information marked * is provided by the applicant, the laboratory is not responsible for its authenticity and this information can affect the validity of the result in the test report. Customer model name, addresses, names, trademarks etc. are included.
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Bay Area Compliance Laboratories Corp. (Shenzhen)

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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
0	2501X79555E-RF-07B	Original Report	2025-12-23

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

Technical Parameters	Radio Type	Bluetooth
	Modulation Type	GFSK, $\pi/4$ -DQPSK, 8DPSK
	Frequency Range	2402-2480MHz
	Rated Output Power	Right:0.01 mW/MHz
	Antenna Gain[#]	1.7 dBi (It is provided by the applicant)
Nominal Power Supply		DC 3.7V from battery or DC 5V from Charging case
Sample serial number		3AOC-1 (Assigned by BACL, Shenzhen)
Sample/EUT Status		Good condition
Adapter Information		N/A
Note:The testing data for Right ear.		

Objective

The objective of the manufacturer is to demonstrate compliance with Certification Ordinance Article 2-1-19, rules and limits for this device including:

- Frequency Error
- Occupied Bandwidth and Spreading Bandwidth
- Transmitter Spurious Emission and Unwanted Emission Intensity
- Antenna Output Power And Output Power Tolerance
- Receiver Spurious Emission Strength
- Frequency Hopping Dwell Time
- Interference Prevention Function
- Construction Protection Confirmation

Test Method

MIC Notice No.88 Appendix No.43

Measurement Uncertainty

Item	Expanded Measurement uncertainty
Frequency Error	56.6Hz(k=2, 95% level of confidence)
Occupied Channel Bandwidth	109.2kHz(k=2, 95% level of confidence)
RF output power, conducted	0.86dB(k=2, 95% level of confidence)
Unwanted Emission, conducted	1.60dB(k=2, 95% level of confidence)
Duty Cycle	±1%
Temperature	±1°C
Supply voltages	±0.4%
Humidity	±1%

Note: The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval. Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 5F(B-West) , 6F, 7F, the 3rd Phase of Wan Li Industrial Building D, Shihua Rd, FuTian Free Trade Zone, Shenzhen, China.

Each test item follows test standards and with no deviation.

EUT TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in a testing mode which was selected by manufacturer.

Normal/Extreme Voltage Condition [#]		
NV	Normal Voltage	3.7
LV	Low Voltage	3.5
HV	High Voltage	4.2
Note: extreme voltage test conditions were declared by manufacturer.		
The EUT works with a battery, power deviation of the RF circuit is less than 1% when extreme voltage supplied, therefore the test only performed at normal condition. Details as following:		
Voltage Condition	Input (V _{DC})	RF System Voltage (V _{DC})
NV	3.7	3.3
LV	3.5	3.3
HV	4.2	3.3

EUT Exercise Software

Exercise Software [#]	FCC_assist_1.0.2.2
Power Level [#]	7

Equipment Modifications

No modification was made to the EUT tested.

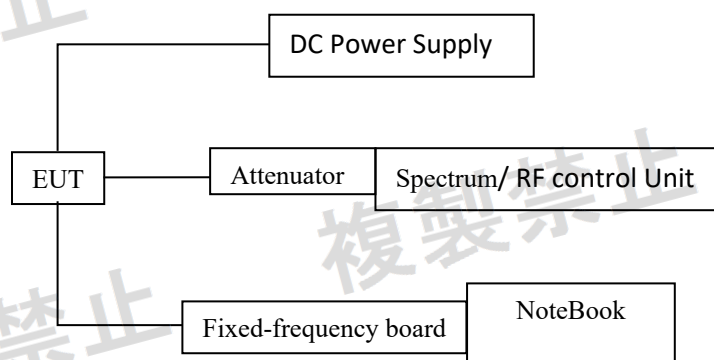
Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
DELL	Notebook	Latitude E6410	11429208685
instek	DC Power Supply	GPS-3030DD	EM832096
TELESKY	Fixed-frequency board	CP2102 MODULES	/

External I/O Cable

Cable Description	Length(m)	From/Port	To
Unshielded detachable DC cable*2	0.6	DC Power Supply	EUT
Unshielded detachable DC cable	0.1	Fixed-frequency board	EUT

Configuration of Test Setup



SUMMARY OF TEST RESULTS

MIC Notice No.88 Appendix No.43 Article 2, Paragraph 1, Item 19	Description of Test	Result
1	Frequency Error	Compliant
2	Occupied Bandwidth and Spreading Bandwidth	Compliant
3	Transmitter Spurious Emission and Unwanted Emission Intensity	Compliant
4	Antenna Output Power and Output Power Tolerance	Compliant
5	Receiver Spurious Emission and Unwanted Emission Intensity	Compliant
6	Transmission Antenna Gain	Not Applicable
7	Transmission Radiation Angle Width	Not Applicable
8	Frequency Hopping Dwell Time	Compliant
9	Interference Prevention Function	Compliant
10	Construction Protection Confirmation	Compliant

Not Applicable - This test item was not required for the output power less than 6.91 dBm/MHz (E.I.R.P)

TEST EQUIPMENT LIST

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Authority	Calibration Method
Tonscend	RF control Unit	JS0806-2	19D8060154	2025/07/18	2026/07/17	BACL Cal	c)
instek	DC Power Supply	GPS-3030DD	EM832096	NCR	NCR	/	/
Fluke	Digital Multimeter	287	19000011	2025/04/29	2026/04/28	BACL Cal	c)
Unknown	6dB Attenuator	Unknown	F-03-EM123	2025/06/26	2026/06/25	BACL Cal	d)
Rohde & Schwarz	Spectrum Analyze	FSU26	200982	2025/08/12	2026/08/11	BACL Cal	c)
Rohde & Schwarz	Spectrum Analyzer	FSV40-N	102259	2025/09/01	2026/08/31	CCIC	c)
Rohde& Schwarz	Wideband Radio Communication Tester	CMW500	141718	2025/07/18	2026/07/17	BACL Cal	c)

Note: Calibration Method

a) Calibration conducted by the National Institute of Information and Communications Technology (NICT) or a designated calibration agency under Article 102-18 paragraph (1)

b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992) ~Japan Calibration Service System~

c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1)

d) Calibration conducted by using other equipment that listed above from a) to c)

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

REQUIREMENTS AND TEST PROCEDURES

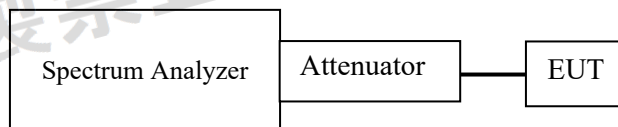
Frequency Error

Limit

50 ppm or below

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- Set the application equipment (EUT) to the measurement frequency.
- The modulation state shall be “continuous carrier wave without modulation” by stopping frequency-hopping mode.

Spectrum Analyzer Conditions

- Center Frequency: Frequency to measure (2402 MHz, 2441MHz, and 2480MHz)
- RBW: 1kHz, VBW: 3kHz
- Span: 300kHz
- Sweep time: Auto
- Log scale: 10dB/Div, Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak
- Sweep mode: Single Sweep
- Marker: Spot

If the EUT can't set at un-modulation mode, measure the 10dBc center frequency.

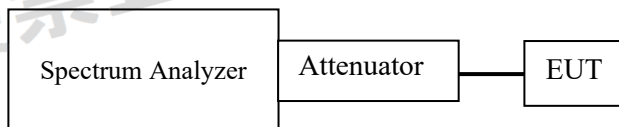
Occupied Bandwidth and Spreading Bandwidth

Limit

- Occupied bandwidth: FH $\leq$ 83.5 MHz; OFDM, DS $\leq$ 26 MHz; Others $\leq$ 26 MHz
- Spread Bandwidth: $\geq$ 500 kHz (FH,DS), Spread factor $>$ 5.

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous frequency-hopping mode” by spread spectrum.

Spectrum Analyzer Conditions

- RBW: 300 kHz
- VBW: 300 kHz
- Sweep time: Auto(Minimum time to ensure measurement accuracy.)
- Log scal: 10dB/Div
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak, Sweep mode: Continuous

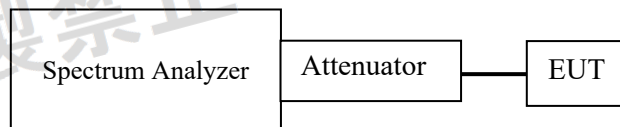
Transmitter Spurious Emission Strength and Unwanted Emission Intensity

Limit

- $f < 2387 \text{ MHz}$, $f > 2496.5 \text{ MHz}$: $\leq 2.5 \mu\text{W/MHz}$
- $2387 \text{ MHz} \leq f \leq 2400 \text{ MHz}$; $2483.5 \text{ MHz} < f \leq 2496.5 \text{ MHz}$: $\leq 25 \mu\text{W/MHz}$

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be in continuously transmitting mode.

Spectrum Analyzer Conditions

- Span: Measuring Frequency Range
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto(Minimum time to ensure measurement accuracy.)
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak

If the measured value is under the technical standard value, do not need to measure more detail.

Note: $2.5 \mu\text{W/MHz} = 0.25 \mu\text{W}/100\text{kHz}$

Antenna Output Power and Antenna Power Tolerance

Limit

- $\leq 3 \text{ mW /MHz}$ (FHSS from 2402-2480 MHz)
- $\leq 10 \text{ mW/MHz}$ (OFDM, DSSS from 2400-2483.5 MHz)
- $\leq 10 \text{ mW}$ (other from 2400-2483.5 MHz)
- $\text{EIRP} \leq 6.91 \text{ dBm/MHz}$

The Output Power Tolerance must be within +20%, -80%.

Test Procedure

For FHSS UUT:

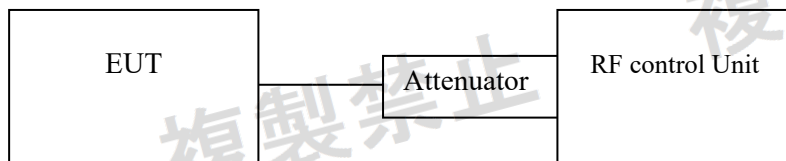
Step 1: Measure the total power by Power Meter in a state of hopping mode

Step 2: Set the power meter to trace average across the pulse on period, record the reading level on power meter.

Step 3: Calculate the mean power per 1MHz by dividing the reading level by spread bandwidth.

Output Power Density (mW/MHz) = Reading (mW) / Spread Bandwidth (MHz)

Test Setup Block diagram



Note: the power meter was integrated in the RF control Unit.

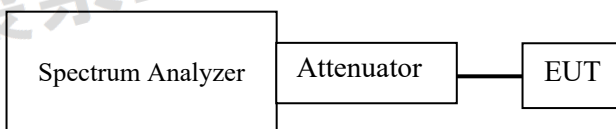
Receiver Spurious Emission and Unwanted Emission Intensity

Limit

- $\leq 4 \text{ nW}$ ($30 \text{ MHz} \leq f \leq 1000 \text{ MHz}$)
- $\leq 20 \text{ nW}$ ($1 \text{ GHz} \leq f \leq 12.5 \text{ GHz}$)

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous receiving mode”.

Spectrum Analyzer Conditions

- Start Frequency: Start Frequency of frequency range to measure (30MHz or 1GHz)
- Stop Frequency: Stop Frequency of frequency range to measure (1GHz or 12.5GHz)
- Span: AUTO (Measurement Range)
- RBW: 100 kHz, VBW: 100 kHz for Frequency < 1 GHz
- RBW: 1MHz, VBW: 1MHz for Frequency > 1 GHz
- Sweep time: AUTO or more
- Sweep mode: Auto Sweep
- Detection: Positive Peak
- Reference Level: Enough level for maximum dynamic range

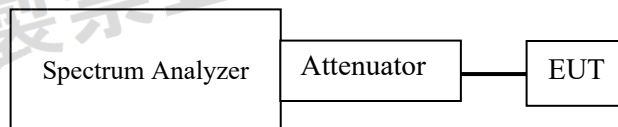
Frequency Hopping Dwell Time

Applicable Standard

According to Radio Law Radio Equipment Regulations Article 49-20, frequency dwell time is 0.4 seconds or below.

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- Set the application equipment (EUT) to the measurement frequency.
- The modulation state shall be “continuous (burst) transmission mode”. If impossible, it shall be “continuous frequency-hopping mode”.

Spectrum Analyzer Conditions

- Step 1:
 - Center Frequency: 2441.0 MHz
 - Span: ZERO SPAN
 - RBW: 1MHz, VBW: 3MHz
 - Log scale: 10dB/Div, Data points: 601points (400 points or more)
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak,
 - Sweep mode: Single
 - Duty cycle= Ton/(Ton+Toff)
- Step 2:
 - Center Frequency: 2441.0 MHz
 - RBW: 1MHz, VBW: 1MHz
 - Span: ZERO SPAN
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak,
 - Sweep mode: Single
 - Sweep time: $0.4 \times \text{SBW}[\text{second}]$

Dwell time = Time per one hopping (On time) * hopping numbers

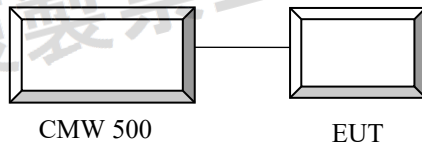
Interference Prevention Function

Requirement

The EUT shall have the interference prevention capability to transmit or to receive the identification automatically, so that sender and receiver shall exclude other equipment.

Test Procedure

Measurement System Diagram



In the case that the EUT has the function of automatically transmitting the identification code:

1. Transmit the predetermined identification codes from EUT
2. Check the transmitted identification codes with the demodulator.

In the case of receiving the identification codes:

1. Transmit the predetermined identification codes from the counterpart.
2. Check if communication is normal
3. Transmit the signal other than predetermined ID codes from the counterpart.
4. Check if the EUT stops the transmission, or if it displays that identification codes are different from the predetermined ones.

TEST DATA AND RESULTS**Test Information:**

Sample No.:	3AOC-1	Test Date:	2025/10/9~2025/12/23
Test Site:	RF	Test Mode:	Transmitting
Tester:	Lee Li&Ethan Bu	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	23.2-23.4	Relative Humidity: (%)	50-51	ATM Pressure: (kPa)	101-101.7
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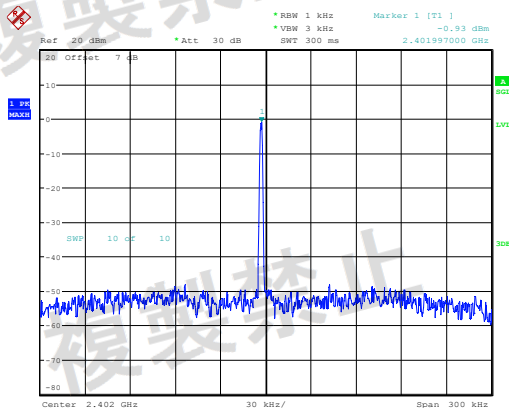
Frequency Error**Test Condition: NV**

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.99700	-1.25	± 50	Pass
	2441	2440.99670	-1.35		Pass
	2480	2479.99640	-1.45		Pass

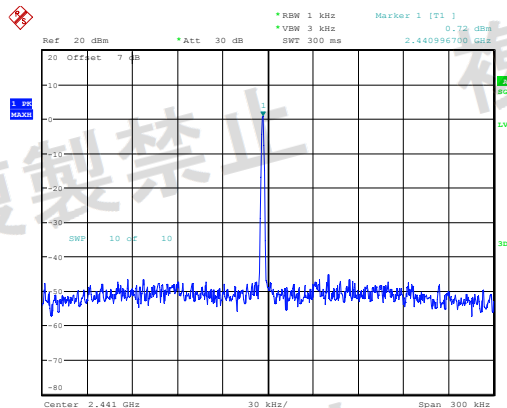
Frequency Tolerance = (Measure Frequency - Frequency)/Frequency*10⁶

Test Condition: NV

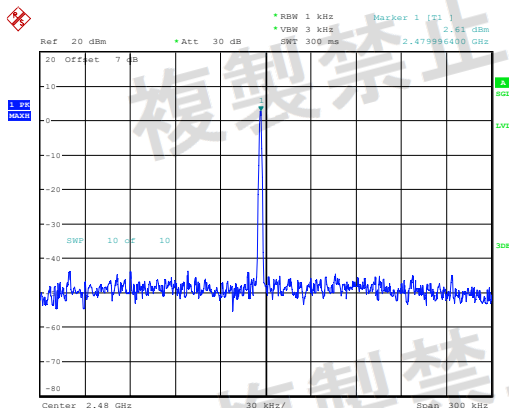
2402MHz

ProjectNo.:2501X79555E-RP(R) Tester:Lee Li
Date: 9.OCT.2025 01:37:38

2441MHz

ProjectNo.:2501X79555E-RP(R) Tester:Lee Li
Date: 9.OCT.2025 01:38:29

2480MHz

ProjectNo.:2501X79555E-RP(R) Tester:Lee Li
Date: 9.OCT.2025 01:39:00

Occupied Bandwidth and Spreading Bandwidth**Test Condition: NV**

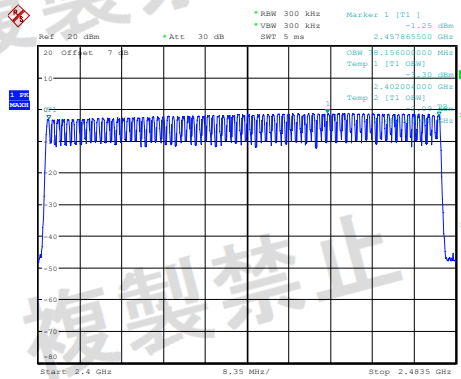
Mode	Packet Type	Occupied bandwidth (MHz)		Spreading bandwidth (MHz)		Spreading factor		Result
		Measured	Limit	Measured	Limit	Measured	Limit	
GFSK	DH1	78.156	≤ 83.5	69.973	≥ 0.5	69.973	> 5	Pass
	DH3	78.156	≤ 83.5	69.973	≥ 0.5	69.973	> 5	Pass
	DH5	78.156	≤ 83.5	70.057	≥ 0.5	70.057	> 5	Pass
$\pi/4$ -DQPSK	2DH1	78.240	≤ 83.5	70.057	≥ 0.5	70.057	> 5	Pass
	2DH3	78.240	≤ 83.5	70.224	≥ 0.5	70.224	> 5	Pass
	2DH5	78.240	≤ 83.5	69.973	≥ 0.5	69.973	> 5	Pass
8DPSK	3DH1	78.323	≤ 83.5	69.973	≥ 0.5	69.973	> 5	Pass
	3DH3	78.240	≤ 83.5	70.057	≥ 0.5	70.057	> 5	Pass
	3DH5	78.323	≤ 83.5	69.639	≥ 0.5	69.639	> 5	Pass

Note: Spread Factor = Spread Bandwidth/modulation rate. The modulation rate: MR=1.

Test Condition: NV

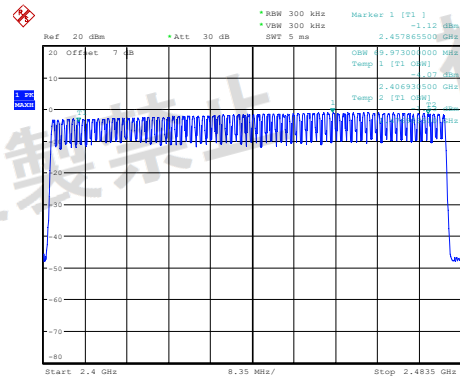
GFSK_Hopping_DH1

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:45:59

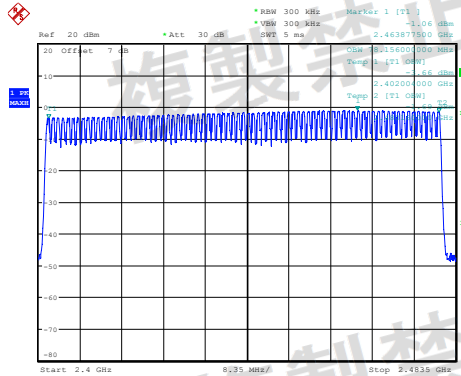
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:47:12

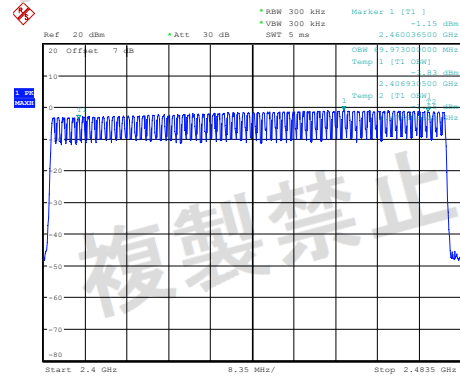
GFSK_Hopping_DH3

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:48:19

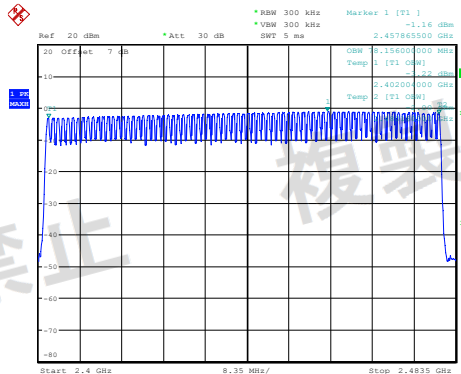
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:49:13

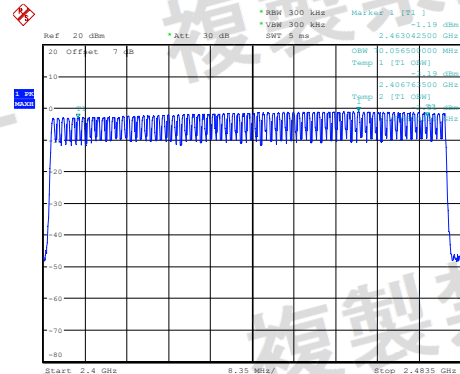
GFSK_Hopping_DH5

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:51:49

Spreading Bandwidth

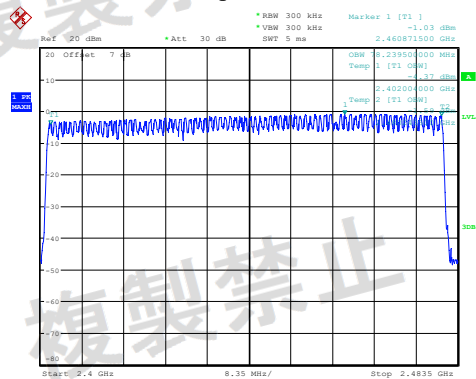


ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:52:40

Test Condition: NV

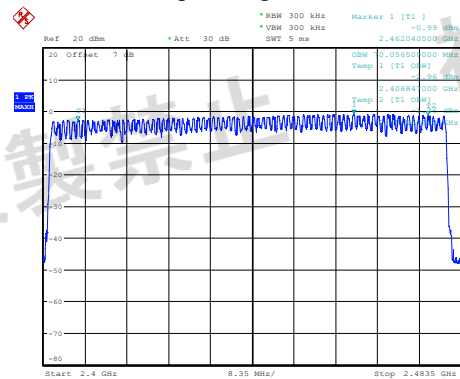
 $\pi/4$ -DQPSK_Hopping_2DH1

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:54:23

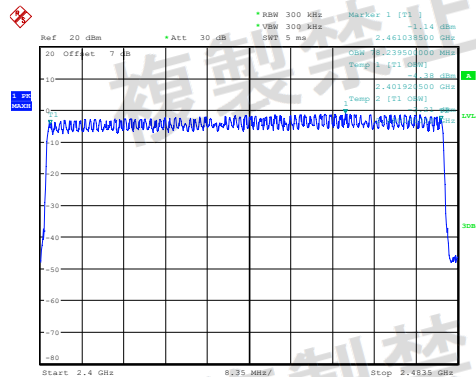
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:55:26

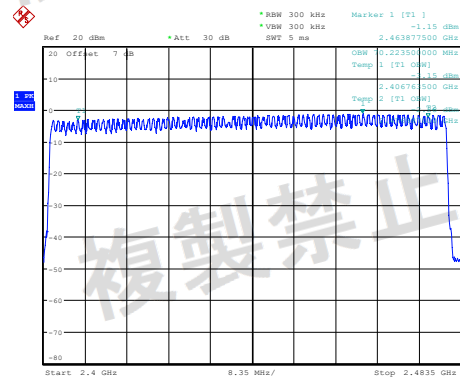
 $\pi/4$ -DQPSK_Hopping_2DH3

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 01:54:34

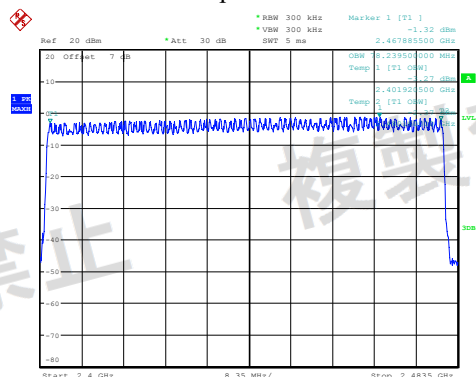
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:00:03

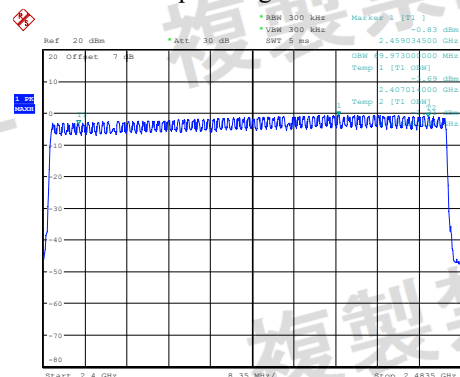
 $\pi/4$ -DQPSK_Hopping_2DH5

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:02:38

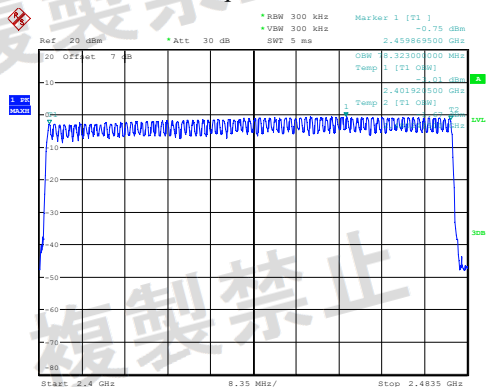
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:06:32

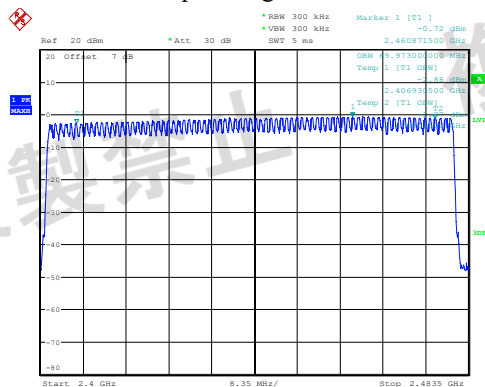
8DPSK_Hopping_3DH1

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:09:08

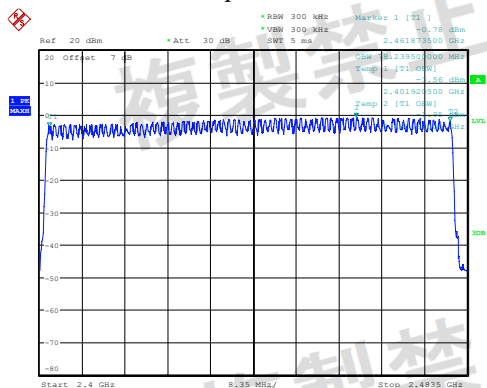
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:12:37

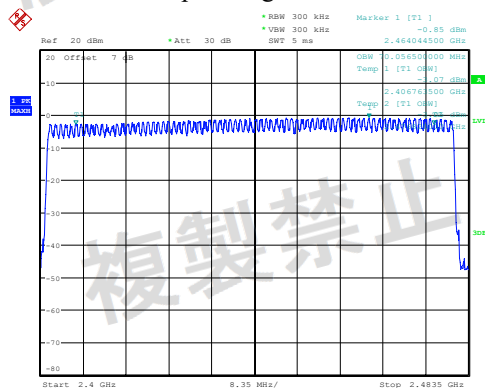
8DPSK_Hopping_3DH3

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:14:36

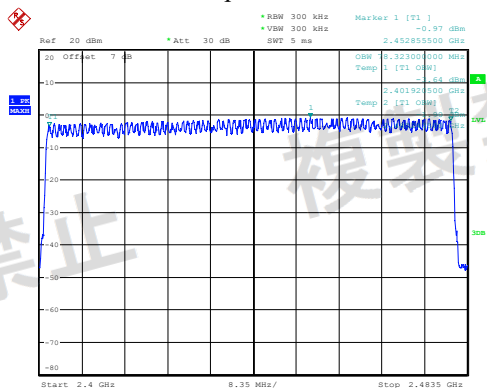
Spreading Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:17:34

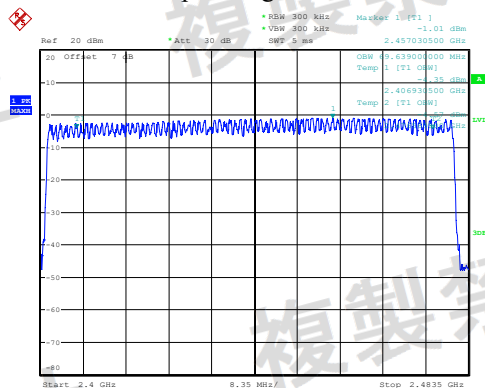
8DPSK_Hopping_3DH5

Occupied Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:21:40

Spreading Bandwidth



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 02:24:19

Transmitter Spurious Emission and Unwanted Emission Intensity**Test Condition: NV, GFSK**

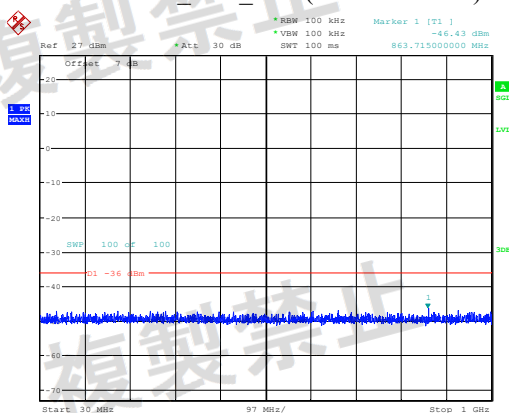
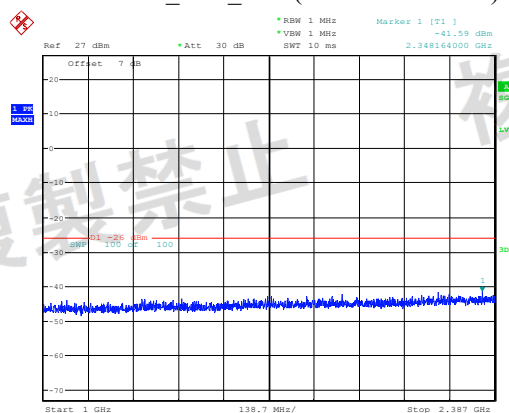
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	863.715	-46.43	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2348.164	-41.59	0.069	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-27.57	1.750	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.7775	-40.84	0.082	25	Pass
	Band V (1MHz)	2496.5	12500	3536.864	-39.69	0.107	2.50	Pass
Middle	Band I (100kHz)	30	1000	331.67	-45.67	0.027	0.25	Pass
	Band II (1MHz)	1000	2387	2023.606	-42.04	0.063	2.50	Pass
	Band III (1MHz)	2387	2400	2398.336	-41.45	0.072	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.1275	-40.95	0.080	25	Pass
	Band V (1MHz)	2496.5	12500	3551.86925	-39.23	0.119	2.50	Pass
High	Band I (100kHz)	30	1000	260.375	-47.21	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	2315.5695	-42.28	0.059	2.50	Pass
	Band III (1MHz)	2387	2400	2394.748	-41.74	0.067	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.03	-40.59	0.087	25	Pass
	Band V (1MHz)	2496.5	12500	3586.8815	-40.08	0.098	2.50	Pass

Test Condition: NV, $\pi/4$ -DQPSK

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μ W/RBW)	Limit (μ W/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	45.035	-46.64	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2240.6715	-42.09	0.062	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-25.48	2.831	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.8325	-41.27	0.075	25	Pass
	Band V (1MHz)	2496.5	12500	3481.84475	-39.93	0.102	2.50	Pass
Middle	Band I (100kHz)	30	1000	986.42	-47.08	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2338.455	-41.67	0.068	2.50	Pass
	Band III (1MHz)	2387	2400	2395.7165	-41.00	0.079	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2495.5575	-40.98	0.080	25	Pass
	Band V (1MHz)	2496.5	12500	3571.87625	-39.03	0.125	2.50	Pass
High	Band I (100kHz)	30	1000	369.985	-47.14	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	2369.6625	-41.00	0.079	2.50	Pass
	Band III (1MHz)	2387	2400	2389.158	-41.20	0.076	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.721	-38.32	0.147	25	Pass
	Band V (1MHz)	2496.5	12500	2611.54025	-38.37	0.146	2.50	Pass

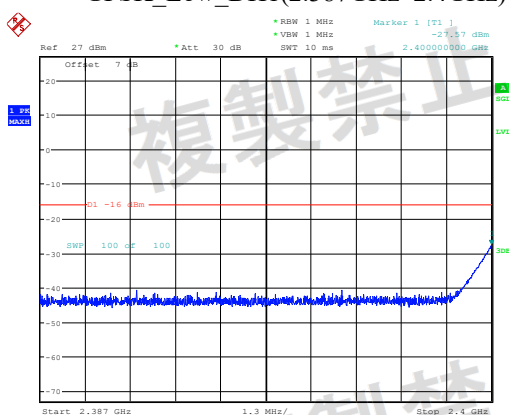
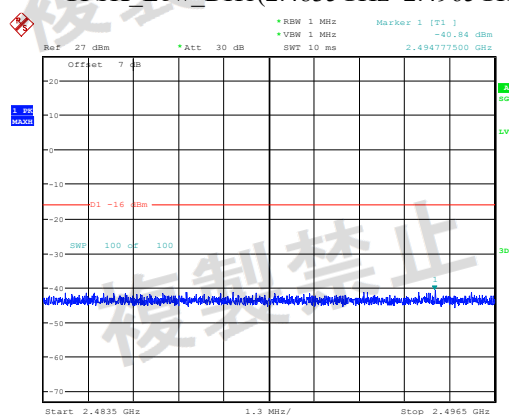
Test Condition: NV, 8DPSK

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μ W/RBW)	Limit (μ W/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	326.82	-46.85	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2212.238	-41.68	0.068	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9935	-25.30	2.951	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.332	-41.31	0.074	25	Pass
	Band V (1MHz)	2496.5	12500	3556.871	-40.21	0.095	2.50	Pass
Middle	Band I (100kHz)	30	1000	446.13	-41.83	0.066	0.25	Pass
	Band II (1MHz)	1000	2387	1887.68	-41.54	0.070	2.50	Pass
	Band III (1MHz)	2387	2400	2393.032	-40.03	0.099	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.826	-40.85	0.082	25	Pass
	Band V (1MHz)	2496.5	12500	3181.73975	-39.72	0.107	2.50	Pass
High	Band I (100kHz)	30	1000	96.93	-46.31	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2339.1485	-41.82	0.066	2.50	Pass
	Band III (1MHz)	2387	2400	2387.793	-41.54	0.070	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.6495	-40.01	0.100	25	Pass
	Band V (1MHz)	2496.5	12500	3586.8815	-40.04	0.099	2.50	Pass

Test Condition: NV**GFSK_Low_DH1(30MHz~1GHz)****GFSK_Low_DH1(1GHz~2.387GHz)**

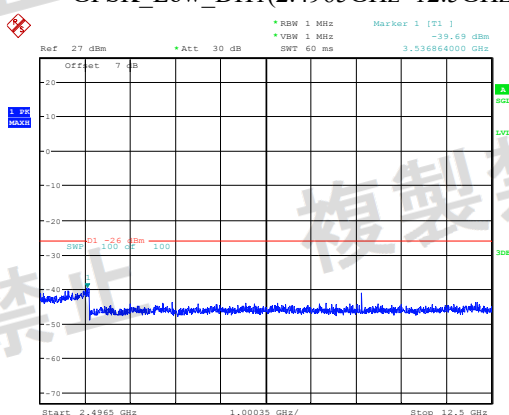
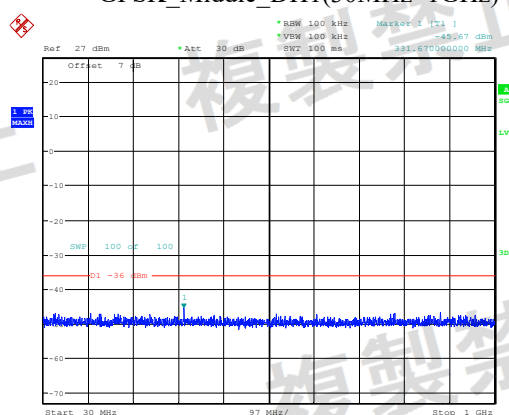
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:06:55

ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:07:10

GFSK_Low_DH1(2.387GHz~2.4GHz)**GFSK_Low_DH1(2.4835GHz~2.4965GHz)**

ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:07:22

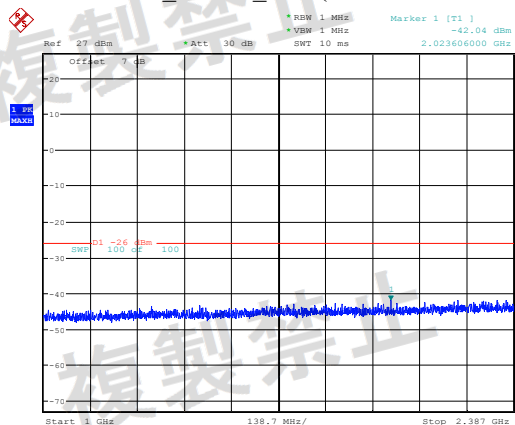
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:07:34

GFSK_Low_DH1(2.4965GHz~12.5GHz)**GFSK_Middle_DH1(30MHz~1GHz)**

ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:08:03

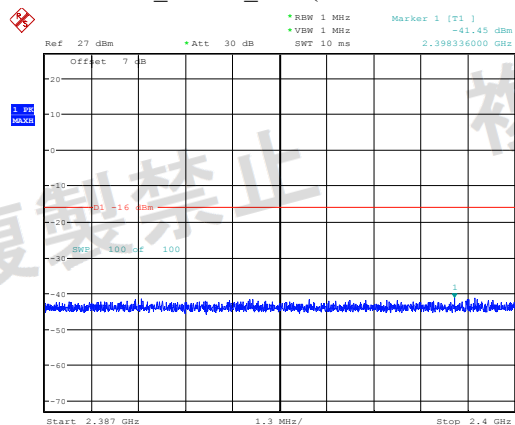
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:08:17

GFSK_Middle_DH1(1GHz~2.387GHz)



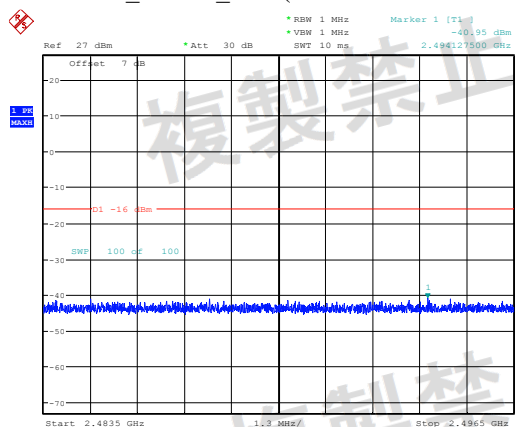
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Date: 9.OCT.2025 05:08:51

GFSK_Middle_DH1(2.387GHz~2.4GHz)



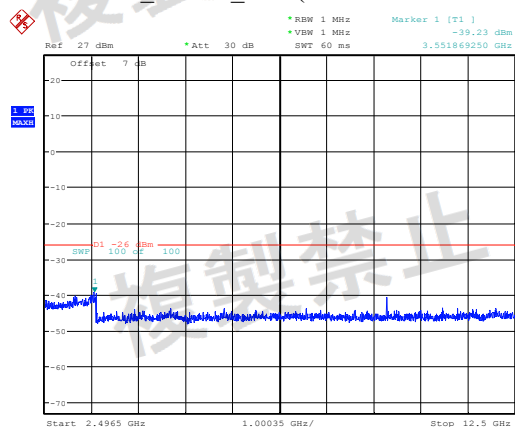
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Date: 9.OCT.2025 05:09:03

GFSK_Middle_DH1(2.4835GHz~2.4965GHz)



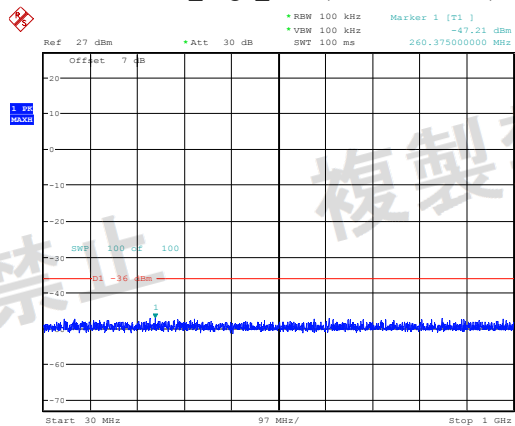
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Date: 9.OCT.2025 05:09:15

GFSK_Middle_DH1(2.4965GHz~12.5GHz)



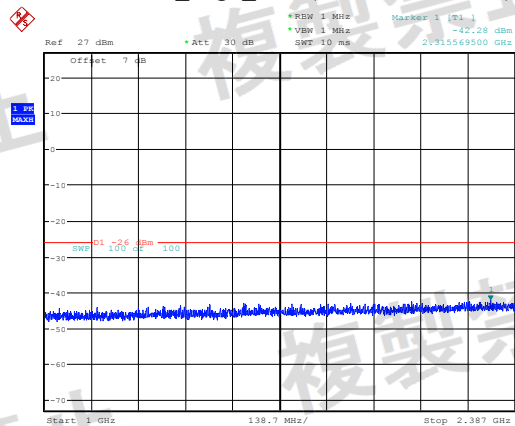
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:09:44

GFSK_High_DH1(30MHz~1GHz)



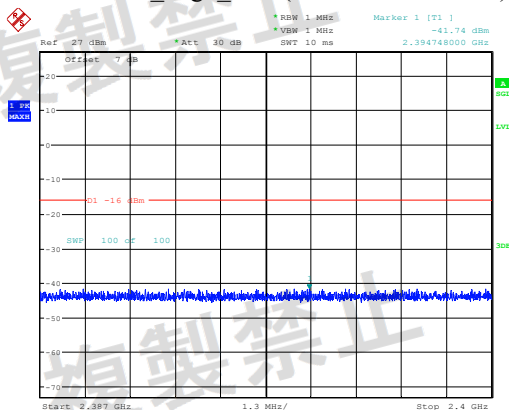
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:10:16

GFSK_High_DH1(1GHz~2.387GHz)



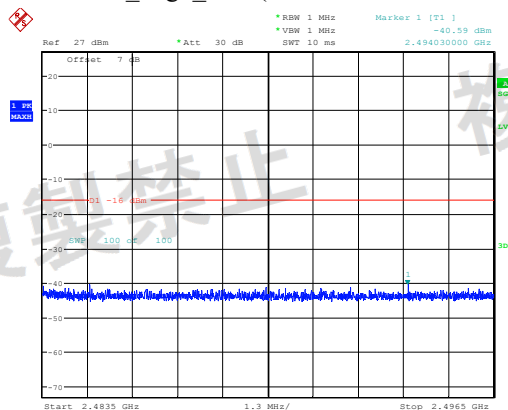
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:10:33

GFSK_High_DH1(2.387GHz~2.4GHz)



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:10:44

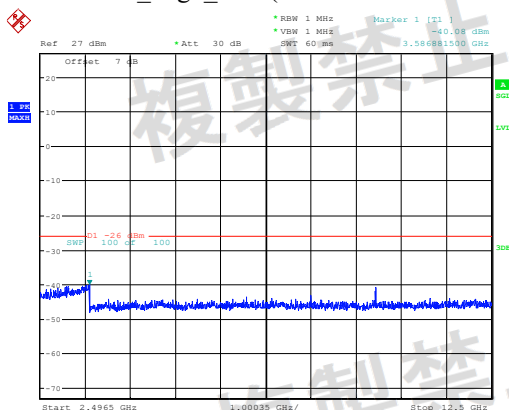
GFSK_High_DH1(2.4835GHz~2.4965GHz)



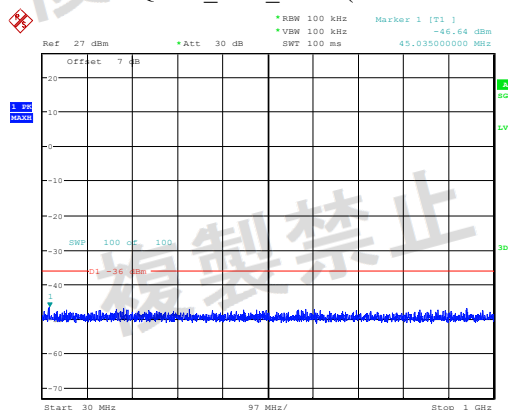
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:10:56

Test Condition: NV

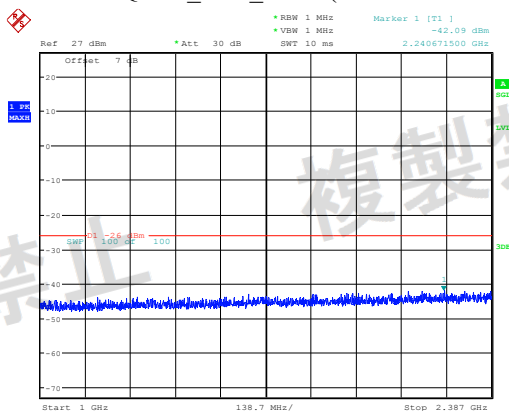
GFSK_High_DH1(2.4965GHz~12.5GHz)



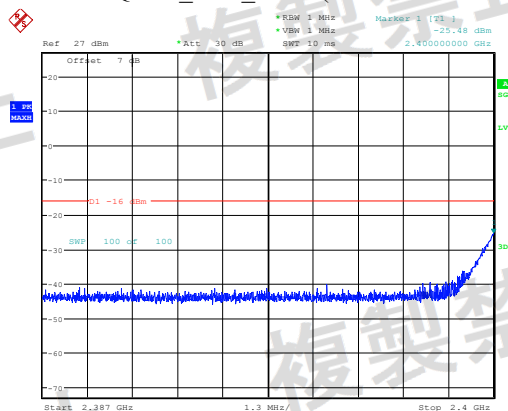
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Date: 9.OCT.2025 05:11:26

 $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

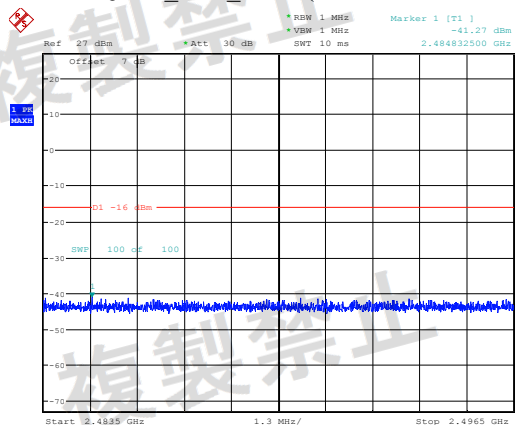
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:12:02

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~2.387GHz)

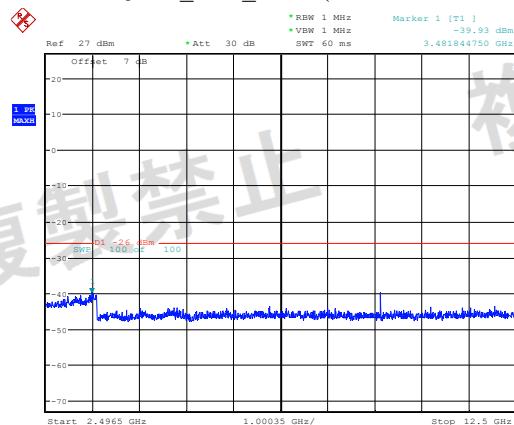
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:12:16

 $\pi/4$ -DQPSK_Low_2DH1(2.387GHz~2.4GHz)

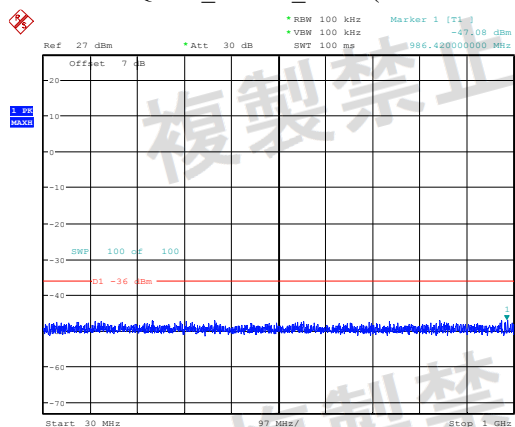
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:12:28

$\pi/4$ -DQPSK_Low_2DH1(2.4835GHz~2.4965GHz)

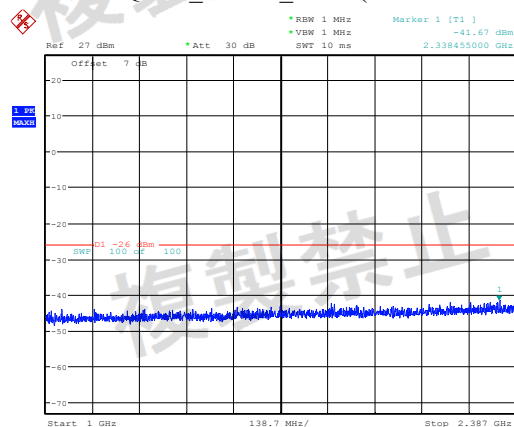
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:12:41

 $\pi/4$ -DQPSK_Low_2DH1(2.4965GHz~12.5GHz)

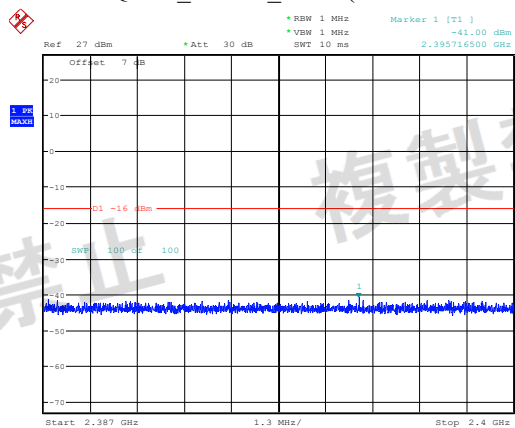
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:13:11

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

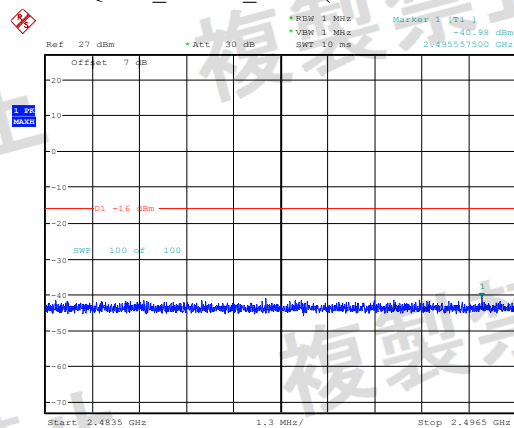
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:14:35

 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~2.387GHz)

ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:14:48

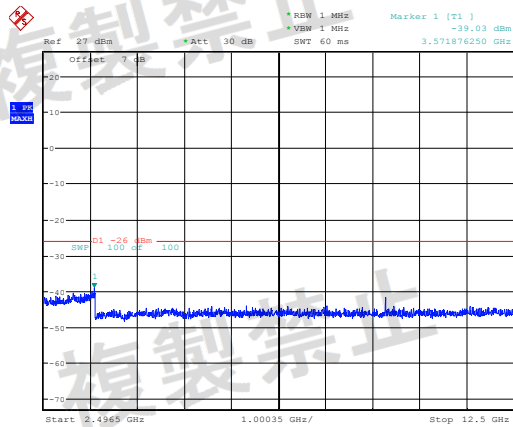
 $\pi/4$ -DQPSK_Middle_2DH1(2.387GHz~2.4GHz)

ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:15:00

 $\pi/4$ -DQPSK_Middle_2DH1(2.4835GHz~2.4965GHz)

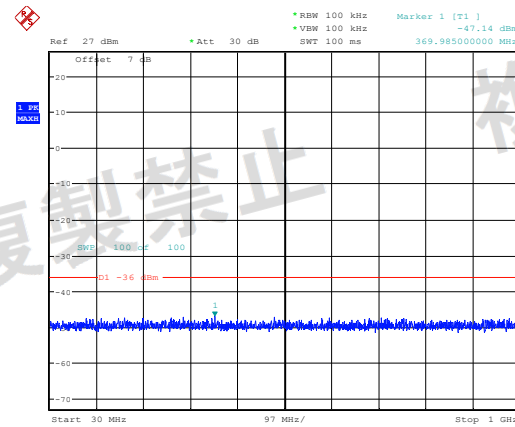
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:15:13

$\pi/4$ -DQPSK_Middle_2DH1(2.4965GHz~12.5GHz)



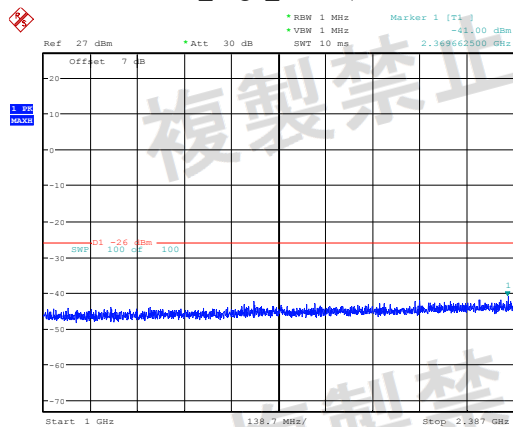
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:15:42

$\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)



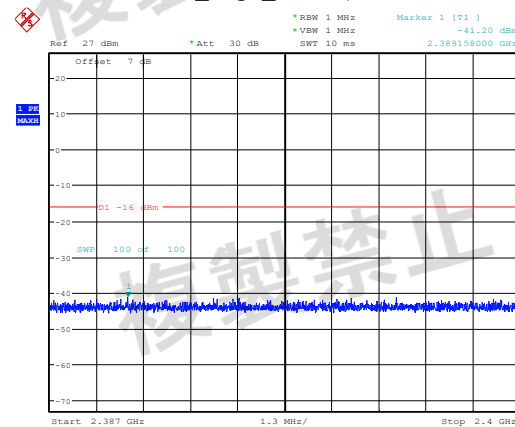
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:17:07

$\pi/4$ -DQPSK_High_2DH1(1GHz~2.387GHz)



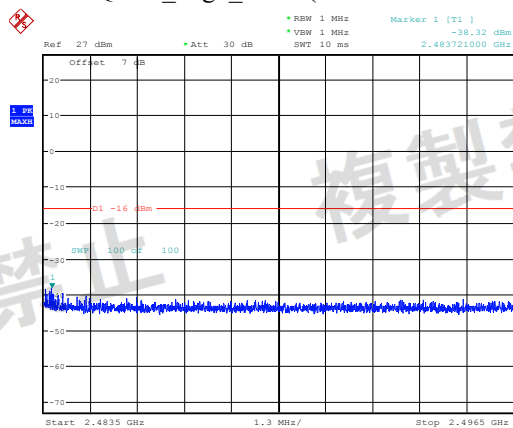
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:17:22

$\pi/4$ -DQPSK_High_2DH1(2.387GHz~2.4GHz)



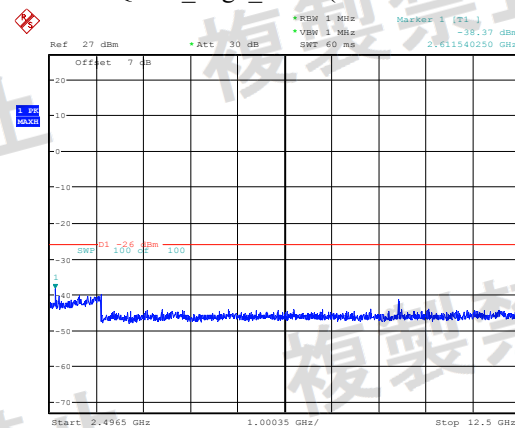
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Date: 9.OCT.2025 05:17:34

$\pi/4$ -DQPSK_High_2DH1(2.4835GHz~2.4965GHz)



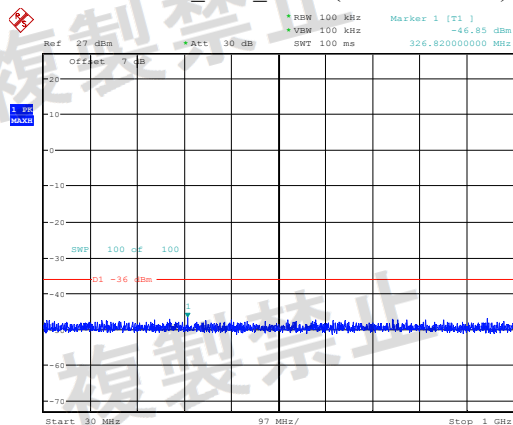
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Date: 9.OCT.2025 05:17:47

$\pi/4$ -DQPSK_High_2DH1(2.4965GHz~12.5GHz)



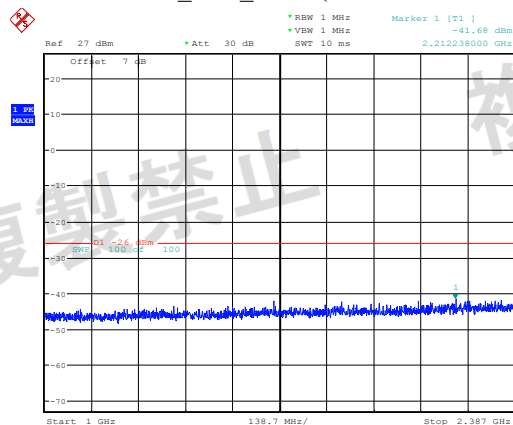
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:18:17

8DPSK_Low_3DH1(30MHz~1GHz)



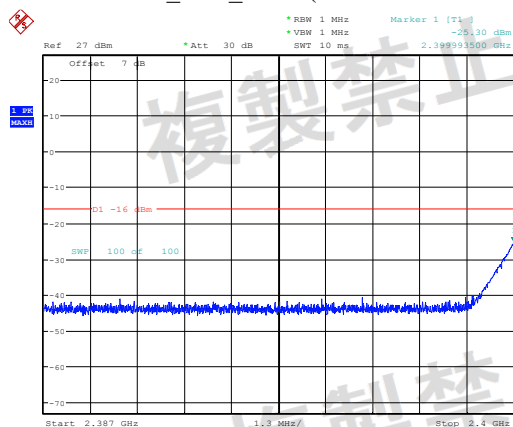
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Date: 9.OCT.2025 05:19:16

8DPSK_Low_3DH1(1GHz~2.387GHz)



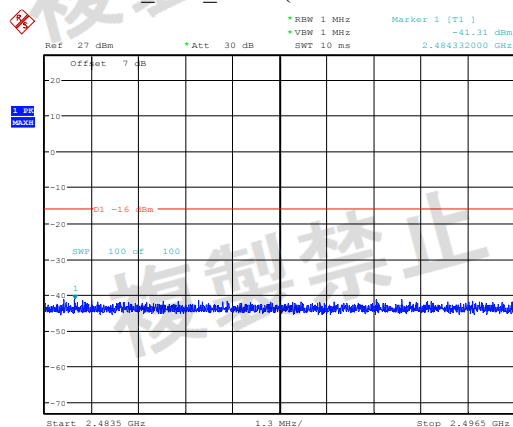
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Date: 9.OCT.2025 05:19:30

8DPSK_Low_3DH1(2.387GHz~2.4GHz)



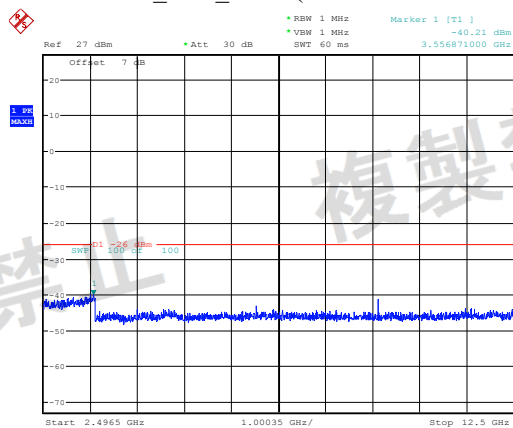
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:19:43

8DPSK_Low_3DH1(2.4835GHz~2.4965GHz)



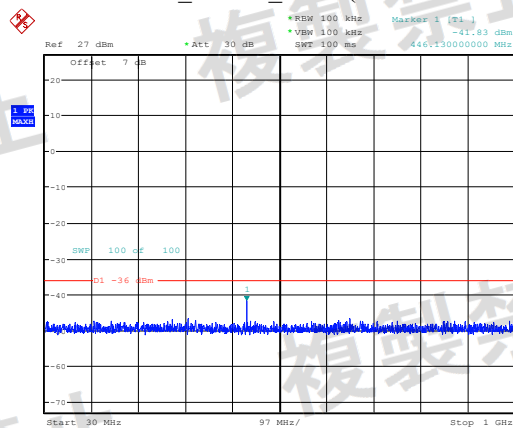
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Date: 9.OCT.2025 05:19:55

8DPSK_Low_3DH1(2.4965GHz~12.5GHz)



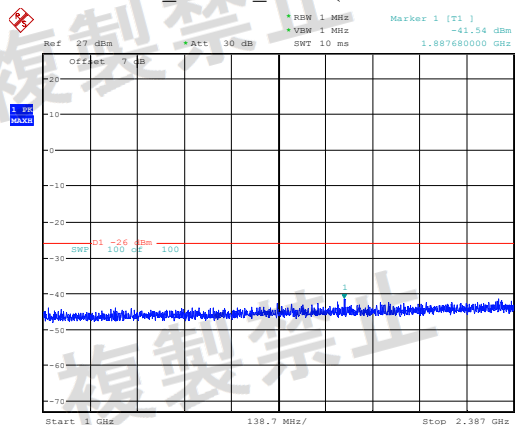
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:20:25

8DPSK_Middle_3DH1(30MHz~1GHz)



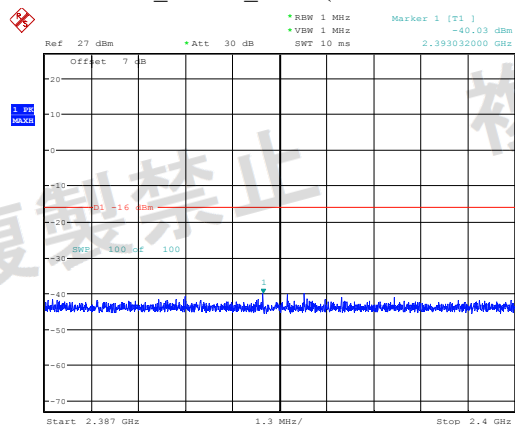
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:21:28

8DPSK_Middle_3DH1(1GHz~2.387GHz)



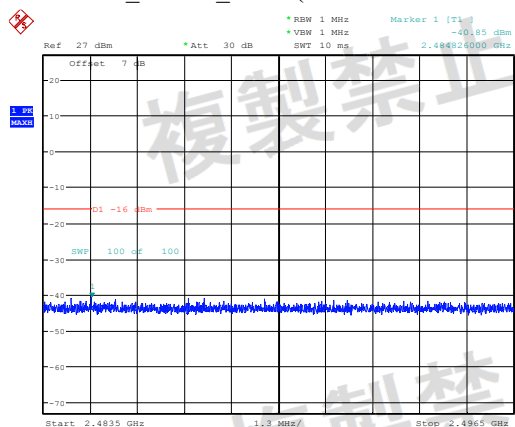
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:21:42

8DPSK_Middle_3DH1(2.387GHz~2.4GHz)



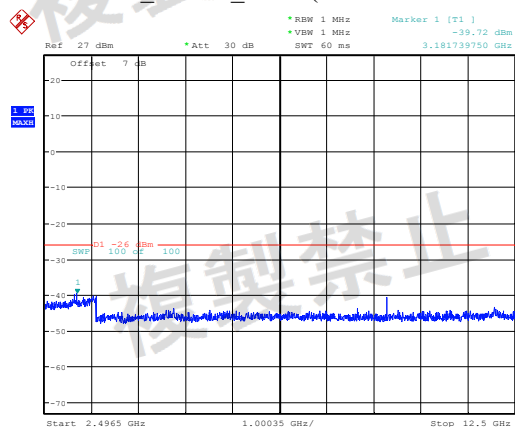
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Date: 9.OCT.2025 05:21:54

8DPSK_Middle_3DH1(2.4835GHz~2.4965GHz)



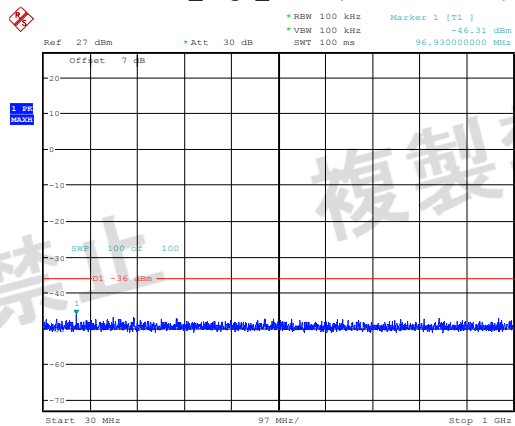
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:22:06

8DPSK_Middle_3DH1(2.4965GHz~12.5GHz)



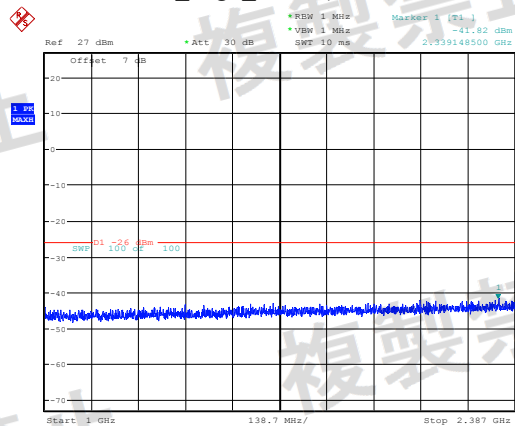
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:22:36

8DPSK_High_3DH1(30MHz~1GHz)



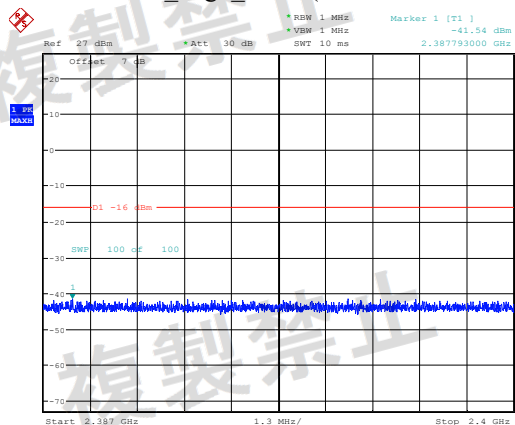
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:24:35

8DPSK_High_3DH1(1GHz~2.387GHz)



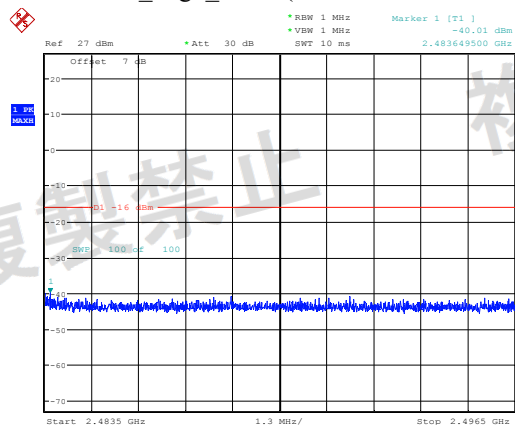
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:24:49

8DPSK_High_3DH1(2.387GHz~2.4GHz)



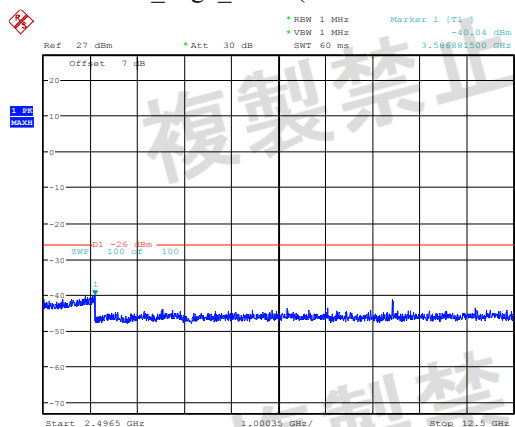
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:25:01

8DPSK_High_3DH1(2.4835GHz~2.4965GHz)



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:25:13

8DPSK_High_3DH1(2.4965GHz~12.5GHz)



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 05:25:42

Antenna Output Power and Output Power Tolerance**Test Condition: NV**

Mode	Antenna gain (dBi)	Declared power (mW/MHz)
GFSK	1.70	0.01
$\pi/4$ DQPSK		0.01
8DPSK		0.01

Test Condition: NV

Mode	Antenna output power (dBm)	Spread bandwidth (MHz)	Antenna output power (mW/MHz)		Antenna output power tolerance(%)		EIRP (dBm/MHz)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
GFSK	-2.48	69.973	0.008	≤ 3	-19.26	-80~+20	-19.23	≤ 6.91	Pass
$\pi/4$ -DQPSK	-4.72	70.057	0.005	≤ 3	-51.86	-80~+20	-21.48	≤ 6.91	Pass
8DPSK	-4.83	69.973	0.005	≤ 3	-53.00	-80~+20	-21.58	≤ 6.91	Pass

Note:

Antenna output power(mW) = $10^{\{\text{Antenna output power(dBm)} / 10\}}$

Antenna output power(mW/MHz) = Antenna output power(mW) / Spread bandwidth(MHz)

Antenna output power Tolerance(%) = (Antenna output power(mW/MHz) - Declared power) / Declared power * 100%

Antenna output power(dBm/MHz) = $10 * \log_{10}\{\text{Antenna output power(mW/MHz)}\}$

EIRP(dBm/MHz) = Antenna output power(dBm/MHz) + Antenna gain.

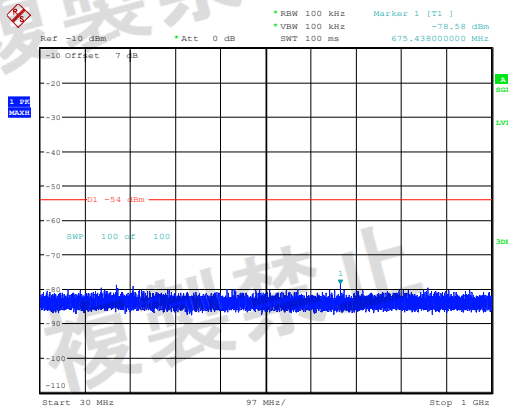
Receiver Spurious Emission and Unwanted Emission Intensity

Test Condition: NV

Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
GFSK	Low	Band I (100kHz)	30	1000	675.438	-78.58	0.014	4	Pass
		Band II (1MHz)	1000	12500	3328.75	-71.54	0.070	20	Pass
	Middle	Band I (100kHz)	30	1000	642.3125	-79.64	0.011	4	Pass
		Band II (1MHz)	1000	12500	3466.75	-69.56	0.111	20	Pass
	High	Band I (100kHz)	30	1000	580.6205	-79.00	0.013	4	Pass
		Band II (1MHz)	1000	12500	3479.975	-71.61	0.069	20	Pass
$\pi/4$ -DQPSK	Low	Band I (100kHz)	30	1000	617.626	-79.41	0.011	4	Pass
		Band II (1MHz)	1000	12500	3144.175	-70.12	0.097	20	Pass
	Middle	Band I (100kHz)	30	1000	775.639	-78.78	0.013	4	Pass
		Band II (1MHz)	1000	12500	3131.525	-71.04	0.079	20	Pass
	High	Band I (100kHz)	30	1000	989.33	-79.58	0.011	4	Pass
		Band II (1MHz)	1000	12500	3542.65	-70.75	0.084	20	Pass
8DPSK	Low	Band I (100kHz)	30	1000	668.551	-79.02	0.013	4	Pass
		Band II (1MHz)	1000	12500	3450.075	-71.41	0.072	20	Pass
	Middle	Band I (100kHz)	30	1000	361.74	-79.86	0.010	4	Pass
		Band II (1MHz)	1000	12500	3524.25	-71.29	0.074	20	Pass
	High	Band I (100kHz)	30	1000	277.0105	-79.12	0.012	4	Pass
		Band II (1MHz)	1000	12500	3494.925	-71.30	0.074	20	Pass

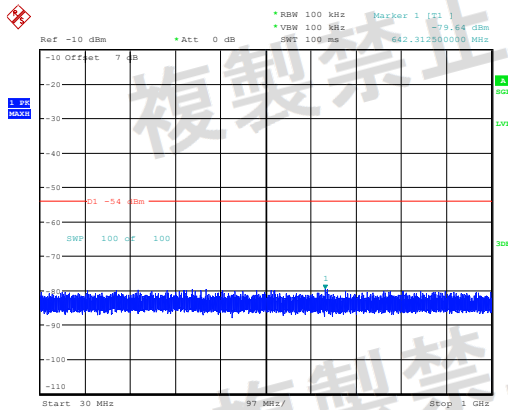
Test Condition: NV

GFSK_Low_DH1(30MHz~1GHz)



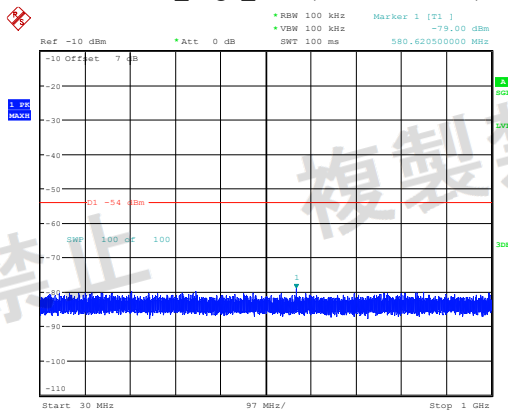
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:13:11

GFSK_Middle_DH1(30MHz~1GHz)



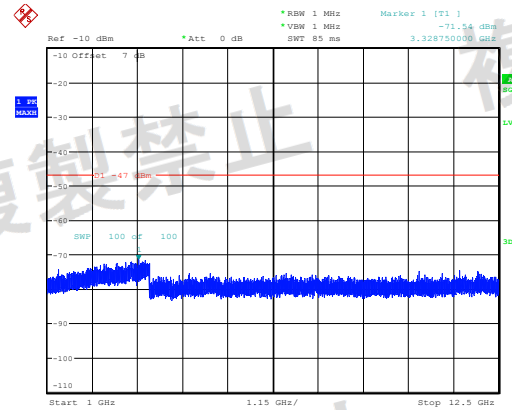
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:14:27

GFSK_High_DH1(30MHz~1GHz)



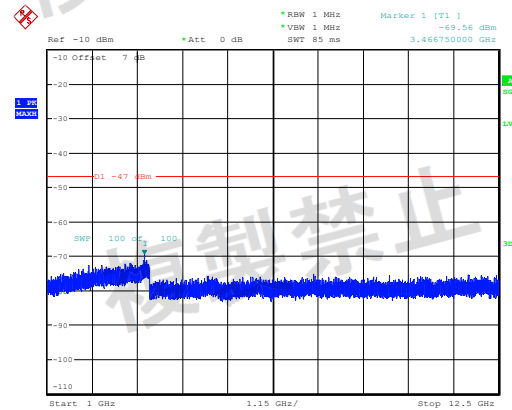
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:15:30

GFSK_Low_DH1(1GHz~12.5GHz)



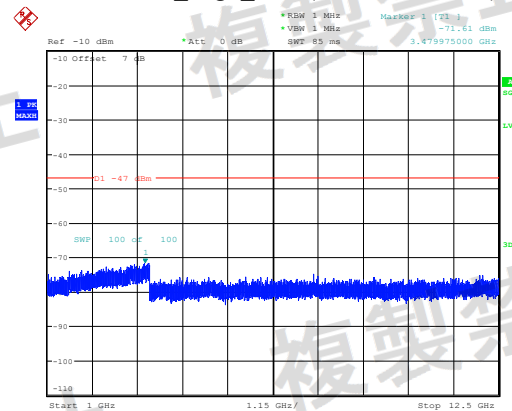
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:13:47

GFSK_Middle_DH1(1GHz~12.5GHz)

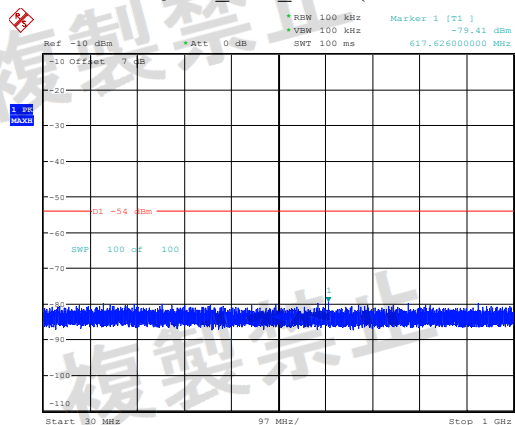


ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:15:02

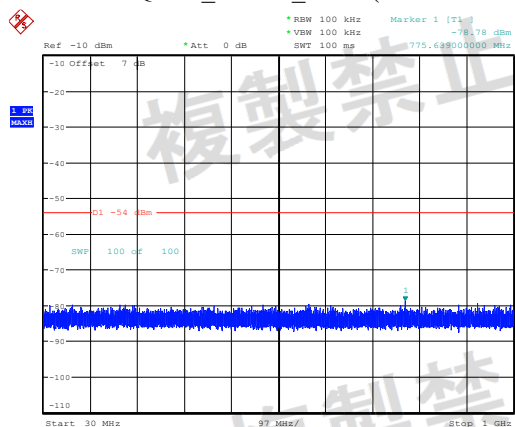
GFSK_High_DH1(1GHz~12.5GHz)



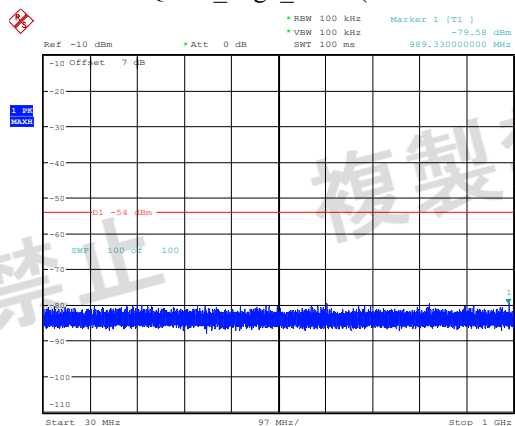
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:16:05

$\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

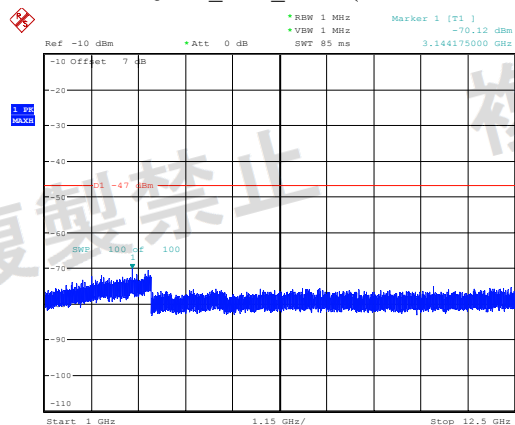
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:16:33

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

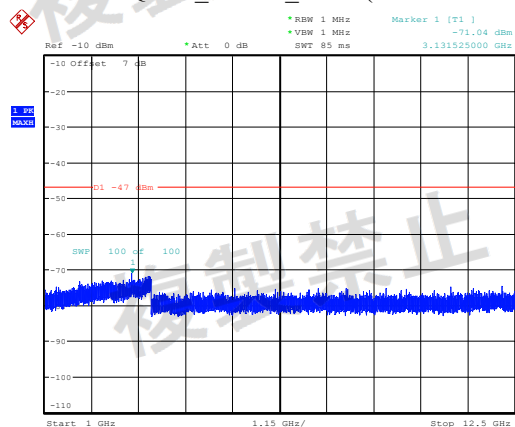
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:17:35

 $\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)

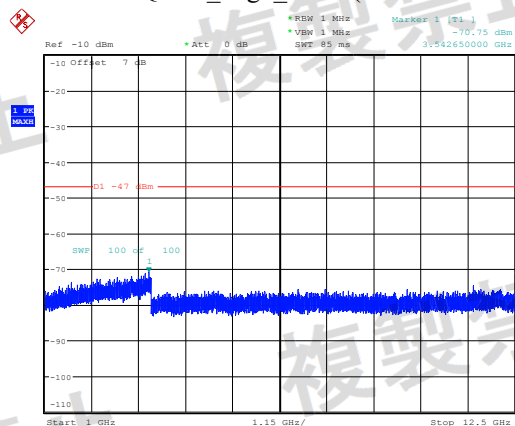
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:18:45

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:17:08

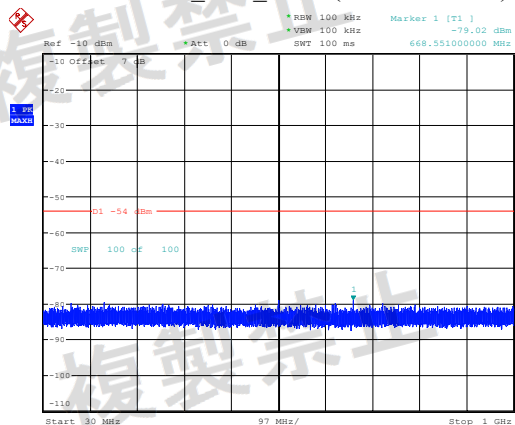
 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:18:10

 $\pi/4$ -DQPSK_High_2DH1(1GHz~12.5GHz)

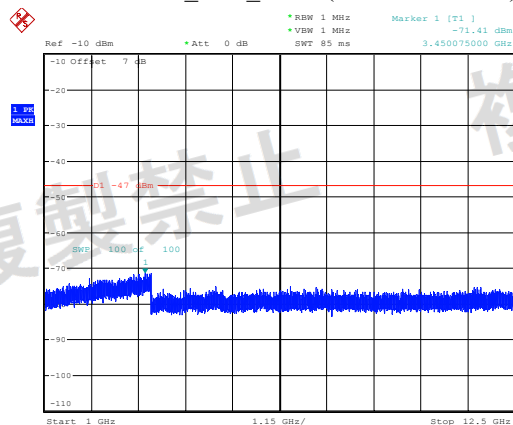
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:19:20

8DPSK_Low_3DH1(30MHz~1GHz)



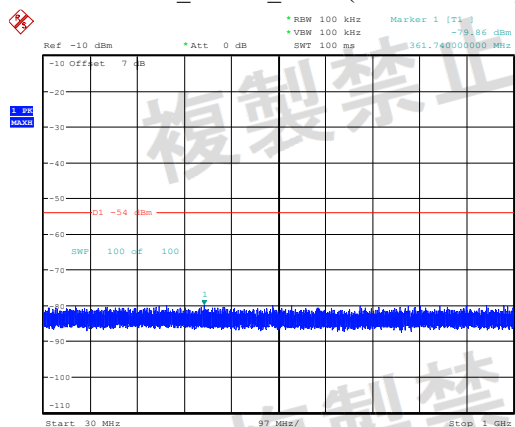
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:19:50

8DPSK_Low_3DH1(1GHz~12.5GHz)



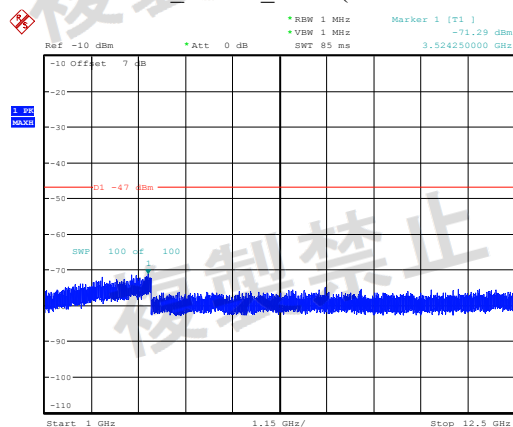
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:20:26

8DPSK_Middle_3DH1(30MHz~1GHz)



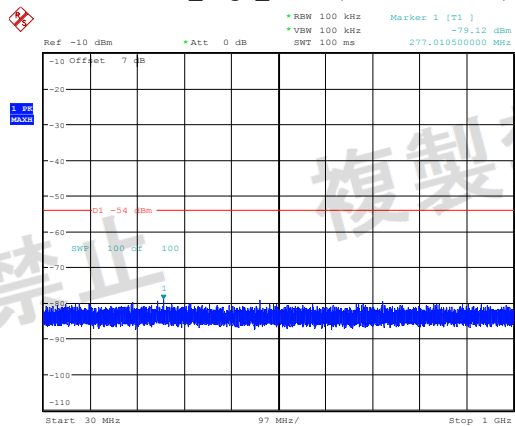
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:20:59

8DPSK_Middle_3DH1(1GHz~12.5GHz)



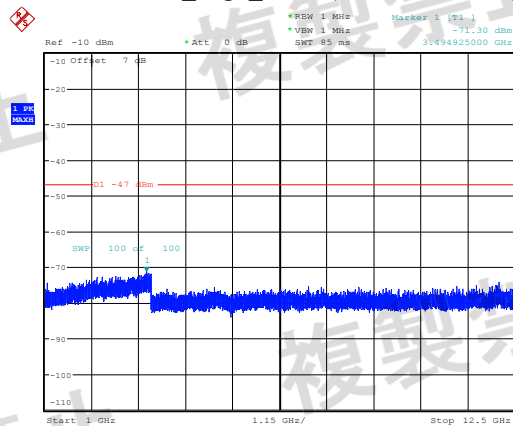
ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:21:34

8DPSK_High_3DH1(30MHz~1GHz)



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:23:26

8DPSK_High_3DH1(1GHz~12.5GHz)



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 06:24:01

Frequency Hopping Dwell Time**Test Condition: NV**

Mode	Packet Type	Spreading bandwidth	Ton (ms)	Observed Period(s)	Hopping Number In Observed Period	Result (s)	Limit(s)	Verdict
GFSK	DH1	69.973	0.413	27.9892	192	0.079	≤ 0.4	Pass
	DH3	69.973	1.680	27.9892	116	0.195		Pass
	DH5	70.057	2.945	28.0228	78	0.230		Pass
$\pi/4$ -DQPSK	2DH1	70.057	0.424	28.0228	194	0.082		Pass
	2DH3	70.224	1.683	28.0896	118	0.199		Pass
	2DH5	69.973	2.950	27.9892	94	0.277		Pass
8DPSK	3DH1	69.973	0.423	27.9892	192	0.081		Pass
	3DH3	70.057	1.683	28.0228	119	0.200		Pass
	3DH5	69.639	2.908	27.8556	85	0.247		Pass

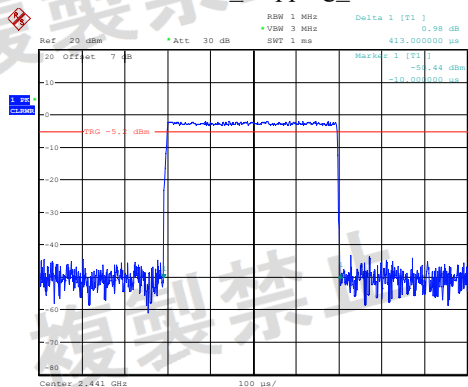
Note:

1. Dwell time = Time per one hopping (Ton) * hopping number (within the time obtained by multiplying the spread rate by 0.4s).

2. The Spread Bandwidth please refer to Occupied Bandwidth and Spreading Bandwidth.

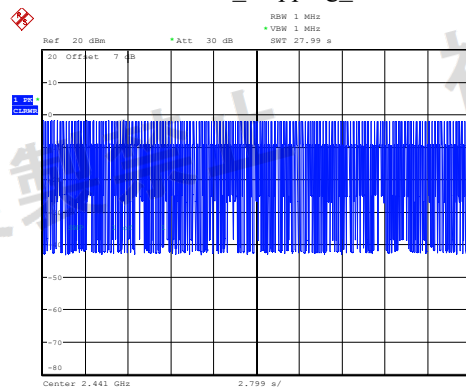
Test Condition: NV

GFSK_Hopping_DH1



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:22:45

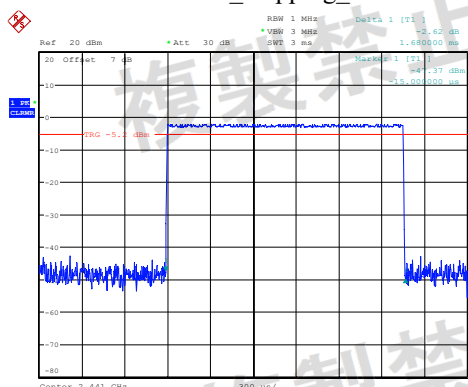
GFSK_Hopping_DH1



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:23:20

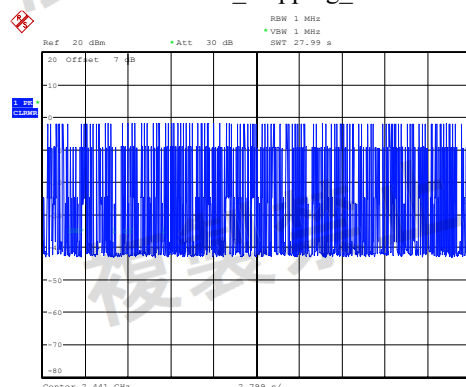
Test Condition: NV

GFSK_Hopping_DH3



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:24:32

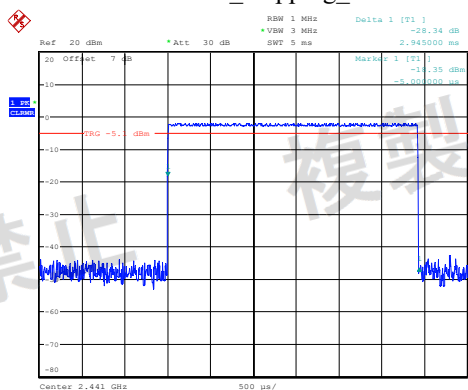
GFSK_Hopping_DH3



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:25:07

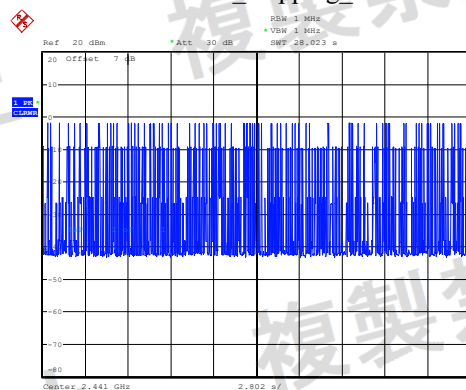
Test Condition: NV

GFSK_Hopping_DH5



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:26:03

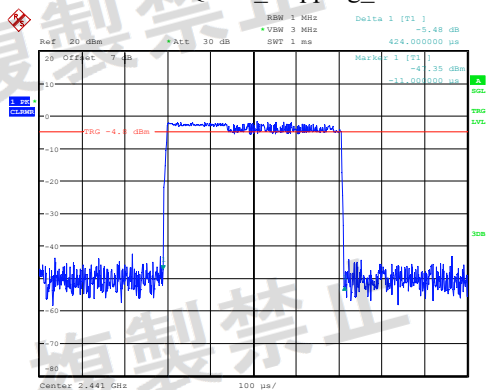
GFSK_Hopping_DH5



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:26:37

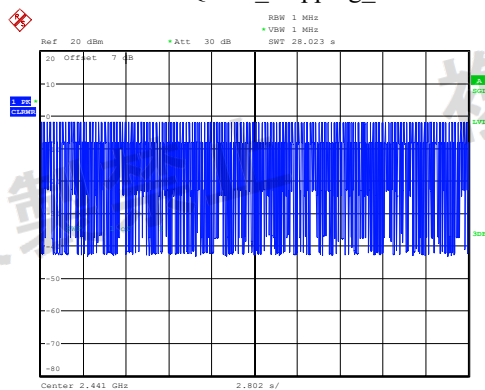
Test Condition: NV

$\pi/4$ -DQPSK_Hopping_2DH1



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:27:36

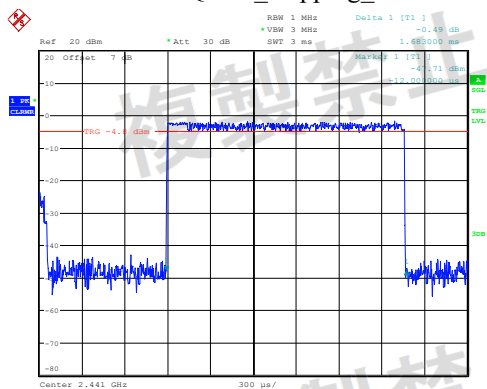
$\pi/4$ -DQPSK_Hopping_2DH1



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:28:11

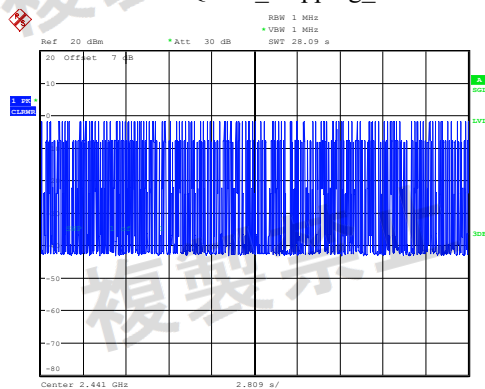
Test Condition: NV

$\pi/4$ -DQPSK_Hopping_2DH3



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:29:00

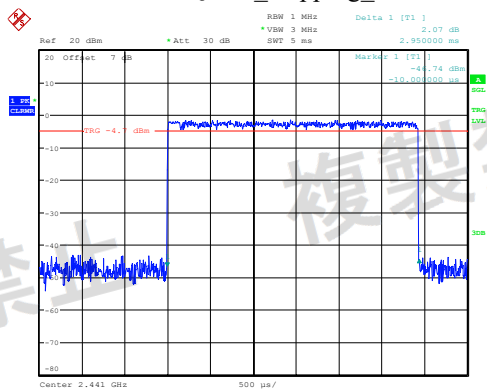
$\pi/4$ -DQPSK_Hopping_2DH3



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:29:35

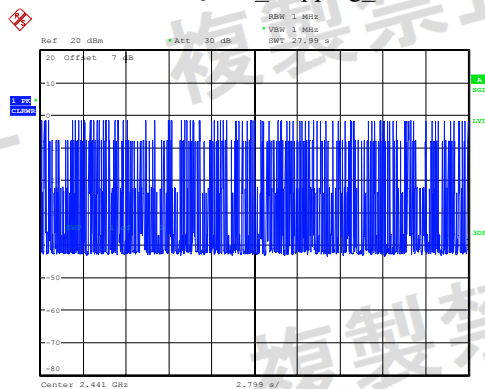
Test Condition: NV

$\pi/4$ -DQPSK_Hopping_2DH5



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:30:39

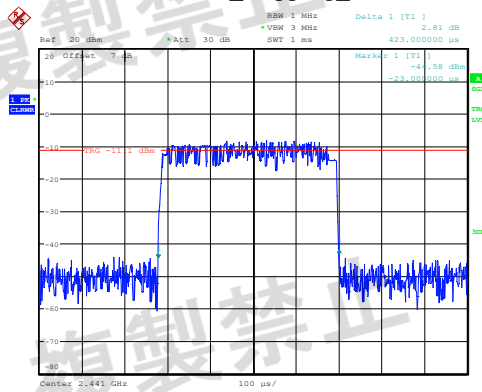
$\pi/4$ -DQPSK_Hopping_2DH5



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:31:14

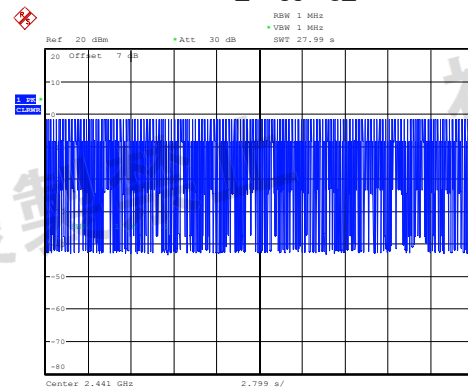
Test Condition: NV

8DPSK_Hopping_3DH1



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:32:07

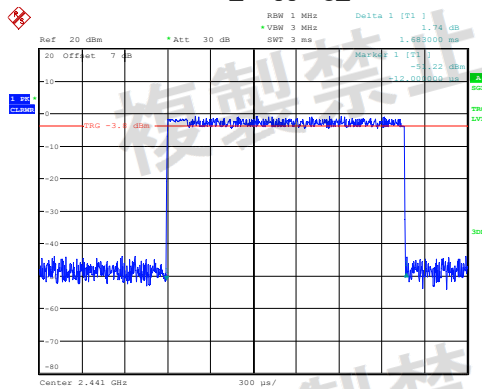
8DPSK_Hopping_3DH1



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:32:42

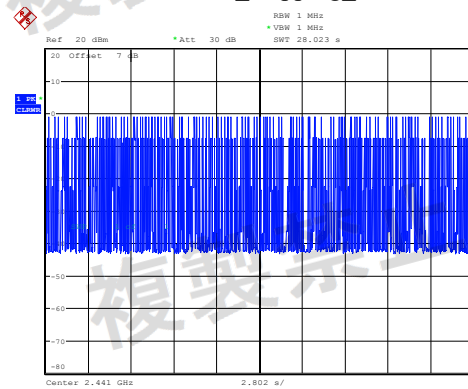
Test Condition: NV

8DPSK_Hopping_3DH3



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:35:06

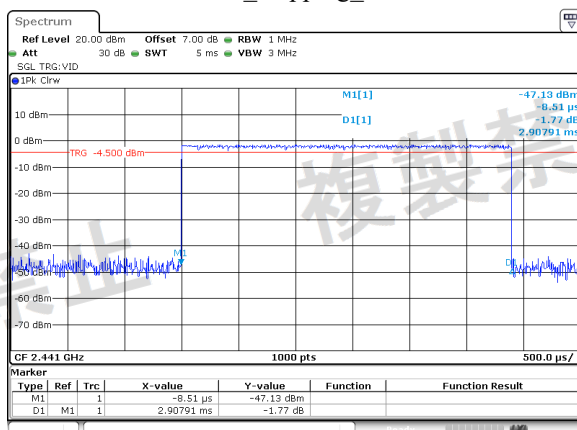
8DPSK_Hopping_3DH3



ProjectNo.:2501X79555E-RF(R) Tester:Lee Li
Date: 9.OCT.2025 03:35:41

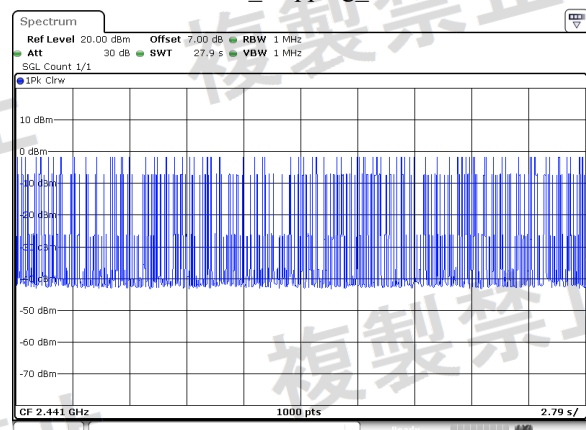
Test Condition: NV

8DPSK_Hopping_3DH5



ProjectNo.:2501X79555E-RF(R) Tester:Ethan Bu
Date: 23.DEC.2025 18:59:29

8DPSK_Hopping_3DH5



ProjectNo.:2501X79555E-RF(R) Tester:Ethan Bu
Date: 23.DEC.2025 19:00:22

Interference Prevention Function**Test Information:**

Sample No.:	3AOC-1	Test Date:	2025/10/9~2025/10/10
Test Site:	RF	Test Mode:	Communicating
Tester:	Lee Li	Test Result:	Good

Environmental Conditions:

Temperature: (°C)	23.4	Relative Humidity: (%)	51	ATM Pressure: (kPa)	101.7
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CONSTRUCTION PROTECTION CONFIRMATION

Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

Confirmation Result

The EUT shell is glued together which can't be opened easily, please see the EUT photos.

EUT PHOTOGRAPHS

Please refer to the attachment 2501X79555E-RF-EXP External photo and 2501X79555E-RF-INP Internal photo.

TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2501X79555E-RF-07B-TSP Test Setup photo.

****END OF REPORT****